Notice of References Cited Application/Control No. 10/814,723 Examiner TAN TRINH Applicant(s)/Patent Under Reexamination OFEK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0114535	06-2004	Hoffmann et al.	370/252
*	В	US-2003/0043071	03-2003	Lilly et al.	342/368
*	С	US-2004/0046571	03-2004	Champion et al.	324/637
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	C	
	<	
	W	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.